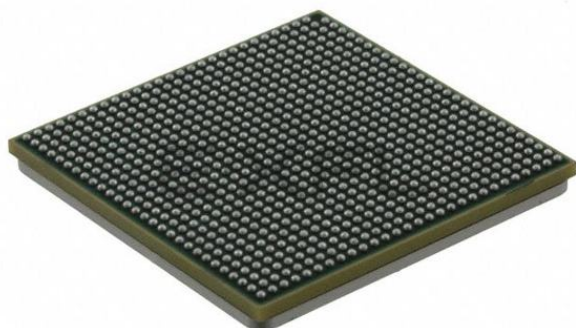




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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.5GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8548epxavhb

- Single inbound doorbell message structure
- Facility to accept port-write messages
- PCI Express interface
 - PCI Express 1.0a compatible
 - Supports x8, x4, x2, and x1 link widths
 - Auto-detection of number of connected lanes
 - Selectable operation as root complex or endpoint
 - Both 32- and 64-bit addressing
 - 256-byte maximum payload size
 - Virtual channel 0 only
 - Traffic class 0 only
 - Full 64-bit decode with 32-bit wide windows
- Pin multiplexing for the high-speed I/O interfaces supports one of the following configurations:
 - 8 PCI Express
 - 4 PCI Express and 4 serial RapidIO
- Power management
 - Supports power saving modes: doze, nap, and sleep
 - Employs dynamic power management, which automatically minimizes power consumption of blocks when they are idle
- System performance monitor
 - Supports eight 32-bit counters that count the occurrence of selected events
 - Ability to count up to 512 counter-specific events
 - Supports 64 reference events that can be counted on any of the eight counters
 - Supports duration and quantity threshold counting
 - Burstiness feature that permits counting of burst events with a programmable time between bursts
 - Triggering and chaining capability
 - Ability to generate an interrupt on overflow
- System access port
 - Uses JTAG interface and a TAP controller to access entire system memory map
 - Supports 32-bit accesses to configuration registers
 - Supports cache-line burst accesses to main memory
 - Supports large block (4-Kbyte) uploads and downloads
 - Supports continuous bit streaming of entire block for fast upload and download
- JTAG boundary scan, designed to comply with IEEE Std. 1149.1™

2 Electrical Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the device. This device is currently targeted to these specifications. Some of these specifications are independent of the I/O cell, but are included for a more complete reference. These are not purely I/O buffer design specifications.

2.1 Overall DC Electrical Characteristics

This section covers the ratings, conditions, and other characteristics.

2.1.1 Absolute Maximum Ratings

The following table provides the absolute maximum ratings.

Table 1. Absolute Maximum Ratings ¹

Characteristic		Symbol	Max Value	Unit	Notes
Core supply voltage		V_{DD}	–0.3 to 1.21	V	—
PLL supply voltage		AV_{DD}	–0.3 to 1.21	V	—
Core power supply for SerDes transceivers		SV_{DD}	–0.3 to 1.21	V	—
Pad power supply for SerDes transceivers		XV_{DD}	–0.3 to 1.21	V	—
DDR and DDR2 DRAM I/O voltage		GV_{DD}	–0.3 to 2.75 –0.3 to 1.98	V	2
Three-speed Ethernet I/O voltage		LV_{DD} (for eTSEC1 and eTSEC2) TV_{DD} (for eTSEC3 and eTSEC4)	–0.3 to 3.63 –0.3 to 2.75 –0.3 to 3.63 –0.3 to 2.75	V	3
PCI/PCI-X, DUART, system control and power management, I ² C, Ethernet MII management, and JTAG I/O voltage		OV_{DD}	–0.3 to 3.63	V	—
Local bus I/O voltage		BV_{DD}	–0.3 to 3.63 –0.3 to 2.75	V	—
Input voltage	DDR/DDR2 DRAM signals	MV_{IN}	–0.3 to ($GV_{DD} + 0.3$)	V	4
	DDR/DDR2 DRAM reference	MV_{REF}	–0.3 to ($GV_{DD}/2 + 0.3$)	V	—
	Three-speed Ethernet I/O signals	LV_{IN} TV_{IN}	–0.3 to ($LV_{DD} + 0.3$) –0.3 to ($TV_{DD} + 0.3$)	V	4
	Local bus signals	BV_{IN}	–0.3 to ($BV_{DD} + 0.3$)	—	—
	DUART, SYSCLK, system control and power management, I ² C, Ethernet MII management, and JTAG signals	OV_{IN}	–0.3 to ($OV_{DD} + 0.3$)	V	4
	PCI/PCI-X	OV_{IN}	–0.3 to ($OV_{DD} + 0.3$)	V	4

Table 1. Absolute Maximum Ratings ¹ (continued)

Characteristic	Symbol	Max Value	Unit	Notes
Storage temperature range	T_{STG}	–55 to 150	°C	—

Notes:

- Functional and tested operating conditions are given in [Table 2](#). Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
- The –0.3 to 2.75 V range is for DDR and –0.3 to 1.98 V range is for DDR2.
- The 3.63 V maximum is only supported when the port is configured in GMII, MII, RMII, or TBI modes; otherwise the 2.75 V maximum applies. See [Section 8.2, “FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI AC Timing Specifications,”](#) for details on the recommended operating conditions per protocol.
- (M,L,O)V_{IN} may overshoot/undershoot to a voltage and for a maximum duration as shown in [Figure 2](#).

2.1.2 Recommended Operating Conditions

The following table provides the recommended operating conditions for this device. Note that the values in this table are the recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Characteristic		Symbol	Recommended Value	Unit	Notes
Core supply voltage		V_{DD}	1.1 V ± 55 mV	V	—
PLL supply voltage		AV_{DD}	1.1 V ± 55 mV	V	1
Core power supply for SerDes transceivers		SV_{DD}	1.1 V ± 55 mV	V	—
Pad power supply for SerDes transceivers		XV_{DD}	1.1 V ± 55 mV	V	—
DDR and DDR2 DRAM I/O voltage		GV_{DD}	2.5 V ± 125 mV 1.8 V ± 90 mV	V	—
Three-speed Ethernet I/O voltage		LV_{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	V	4
		TV_{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	—	4
PCI/PCI-X, DUART, system control and power management, I ² C, Ethernet MII management, and JTAG I/O voltage		OV_{DD}	3.3 V ± 165 mV	V	3
Local bus I/O voltage		BV_{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	V	—
Input voltage	DDR and DDR2 DRAM signals	MV_{IN}	GND to GV_{DD}	V	2
	DDR and DDR2 DRAM reference	MV_{REF}	GND to $GV_{DD}/2$	V	2
	Three-speed Ethernet signals	LV_{IN} TV_{IN}	GND to LV_{DD} GND to TV_{DD}	V	4
	Local bus signals	BV_{IN}	GND to BV_{DD}	V	—
	PCI, DUART, SYSCLK, system control and power management, I ² C, Ethernet MII management, and JTAG signals	OV_{IN}	GND to OV_{DD}	V	3

2.1.3 Output Driver Characteristics

The following table provides information on the characteristics of the output driver strengths. The values are preliminary estimates.

Table 3. Output Drive Capability

Driver Type	Programmable Output Impedance (Ω)	Supply Voltage	Notes
Local bus interface utilities signals	25 25	$BV_{DD} = 3.3\text{ V}$ $BV_{DD} = 2.5\text{ V}$	1
	45(default) 45(default)	$BV_{DD} = 3.3\text{ V}$ $BV_{DD} = 2.5\text{ V}$	
PCI signals	25	$OV_{DD} = 3.3\text{ V}$	2
	45(default)		
DDR signal	18 36 (half strength mode)	$GV_{DD} = 2.5\text{ V}$	3
DDR2 signal	18 36 (half strength mode)	$GV_{DD} = 1.8\text{ V}$	3
TSEC/10/100 signals	45	$L/TV_{DD} = 2.5/3.3\text{ V}$	—
DUART, system control, JTAG	45	$OV_{DD} = 3.3\text{ V}$	—
I2C	150	$OV_{DD} = 3.3\text{ V}$	—

Notes:

1. The drive strength of the local bus interface is determined by the configuration of the appropriate bits in PORIMPSR.
2. The drive strength of the PCI interface is determined by the setting of the PCI_GNT1 signal at reset.
3. The drive strength of the DDR interface in half-strength mode is at $T_j = 105^\circ\text{C}$ and at GV_{DD} (min).

2.2 Power Sequencing

The device requires its power rails to be applied in a specific sequence in order to ensure proper device operation. These requirements are as follows for power-up:

1. V_{DD} , AV_{DD-n} , BV_{DD} , LV_{DD} , OV_{DD} , SV_{DD} , TV_{DD} , XV_{DD}
2. GV_{DD}

All supplies must be at their stable values within 50 ms.

NOTE

Items on the same line have no ordering requirement with respect to one another. Items on separate lines must be ordered sequentially such that voltage rails on a previous step must reach 90% of their value before the voltage rails on the current step reach 10% of theirs.

NOTE

In order to guarantee MCKE low during power-up, the above sequencing for GV_{DD} is required. If there is no concern about any of the DDR signals being in an indeterminate state during power-up, then the sequencing for GV_{DD} is not required.

Table 23. GMII, MII, RMII, TBI, RGMII, RTBI, and FIFO DC Electrical Characteristics

Parameters	Symbol	Min	Max	Unit	Notes
Supply voltage 2.5 V	LV_{DD}/TV_{DD}	2.37	2.63	V	1, 2
Output high voltage ($LV_{DD}/TV_{DD} = \text{Min}$, $I_{OH} = -1.0 \text{ mA}$)	V_{OH}	2.00	$LV_{DD}/TV_{DD} + 0.3$	V	—
Output low voltage ($LV_{DD}/TV_{DD} = \text{Min}$, $I_{OL} = 1.0 \text{ mA}$)	V_{OL}	GND -0.3	0.40	V	—
Input high voltage	V_{IH}	1.70	$LV_{DD}/TV_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	-0.3	0.90	V	—
Input high current ($V_{IN} = LV_{DD}$, $V_{IN} = TV_{DD}$)	I_{IH}	—	10	μA	1, 2, 3
Input low current ($V_{IN} = \text{GND}$)	I_{IL}	-15	—	μA	3

Notes:

1. LV_{DD} supports eTSECs 1 and 2.
2. TV_{DD} supports eTSECs 3 and 4.
3. Note that the symbol V_{IN} , in this case, represents the LV_{IN} and TV_{IN} symbols referenced in [Table 1](#) and [Table 2](#).

8.2 FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI AC Timing Specifications

The AC timing specifications for FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI are presented in this section.

8.2.1 FIFO AC Specifications

The basis for the AC specifications for the eTSEC's FIFO modes is the double data rate RGMII and RTBI specifications, since they have similar performances and are described in a source-synchronous fashion like FIFO modes. However, the FIFO interface provides deliberate skew between the transmitted data and source clock in GMII fashion.

When the eTSEC is configured for FIFO modes, all clocks are supplied from external sources to the relevant eTSEC interface. That is, the transmit clock must be applied to the eTSECn's TSECn_TX_CLK, while the receive clock must be applied to pin TSECn_RX_CLK. The eTSEC internally uses the transmit clock to synchronously generate transmit data and outputs an echoed copy of the transmit clock back out onto the TSECn_GTX_CLK pin (while transmit data appears on TSECn_TXD[7:0], for example). It is intended that external receivers capture eTSEC transmit data using the clock on TSECn_GTX_CLK as a source-synchronous timing reference. Typically, the clock edge that launched the data can be used, since the clock is delayed by the eTSEC to allow acceptable set-up margin at the receiver. Note that there is relationship between the maximum FIFO speed and the platform speed. For more information see [Section 4.5, "Platform to FIFO Restrictions."](#)

Figure 11 shows the MII transmit AC timing diagram.

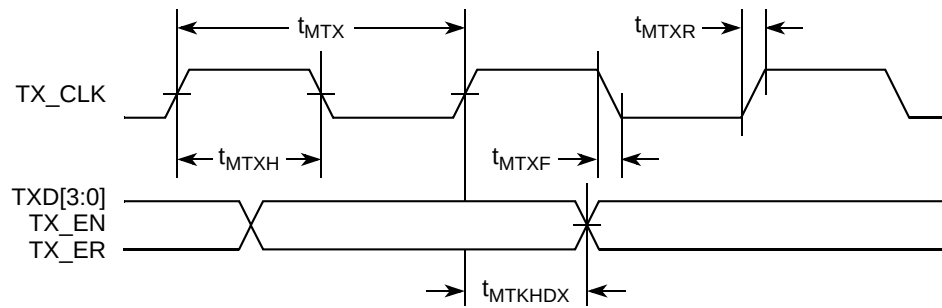


Figure 11. MII Transmit AC Timing Diagram

8.2.3.2 MII Receive AC Timing Specifications

This table provides the MII receive AC timing specifications.

Table 29. MII Receive AC Timing Specifications

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period 10 Mbps	t_{MRX}^2	—	400	—	ns
RX_CLK clock period 100 Mbps	t_{MRX}	—	40	—	ns
RX_CLK duty cycle	t_{MRXH}/t_{MRX}	35	—	65	%
RXD[3:0], RX_DV, RX_ER setup time to RX_CLK	t_{MRDVKH}	10.0	—	—	ns
RXD[3:0], RX_DV, RX_ER hold time to RX_CLK	t_{MRDXKH}	10.0	—	—	ns
RX_CLK clock rise (20%–80%)	t_{MRXR}^2	1.0	—	4.0	ns
RX_CLK clock fall time (80%–20%)	t_{MRXF}^2	1.0	—	4.0	ns

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- Guaranteed by design.

Figure 12 provides the AC test load for eTSEC.

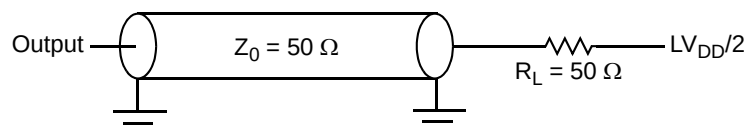


Figure 12. eTSEC AC Test Load

Table 41 describes the timing parameters of the local bus interface at $BV_{DD} = 2.5$ V.

Table 41. Local Bus Timing Parameters ($BV_{DD} = 2.5$ V)—PLL Enabled

Parameter	Symbol ¹	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	7.5	12	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	$t_{LBKSKEW}$	—	150	ps	7, 8
Input setup to local bus clock (except $\overline{LGTA}/UPWAIT$)	$t_{LBIVKH1}$	1.9	—	ns	3, 4
$\overline{LGTA}/LUPWAIT$ input setup to local bus clock	$t_{LBIVKH2}$	1.8	—	ns	3, 4
Input hold from local bus clock (except $\overline{LGTA}/LUPWAIT$)	$t_{LBIXKH1}$	1.1	—	ns	3, 4
$\overline{LGTA}/LUPWAIT$ input hold from local bus clock	$t_{LBIXKH2}$	1.1	—	ns	3, 4
LALE output transition to LAD/LDP output transition (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	2.1	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	2.3	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	2.4	ns	3
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	2.4	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.8	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.8	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.6	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.6	ns	5

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
3. All signals are measured from $BV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
8. Guaranteed by design.

Figure 22 provides the AC test load for the local bus.

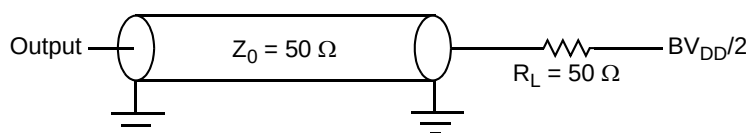


Figure 22. Local Bus AC Test Load

17 PCI Express

This section describes the DC and AC electrical specifications for the PCI Express bus of the MPC8548E.

17.1 DC Requirements for PCI Express SD_REF_CLK and SD_REF_CLK

For more information, see [Section 16.2, “SerDes Reference Clocks.”](#)

17.2 AC Requirements for PCI Express SerDes Clocks

[Table 55](#) lists the AC requirements for the PCI Express SerDes clocks.

Table 55. SD_REF_CLK and SD_REF_CLK AC Requirements

Symbol	Parameter Description	Min	Typ	Max	Unit	Notes
t_{REF}	REFCLK cycle time	—	10	—	ns	1
t_{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles.	—	—	100	ps	—
t_{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location.	–50	—	50	ps	—

Note:

1. Typical based on *PCI Express Specification 2.0*.

17.3 Clocking Dependencies

The ports on the two ends of a link must transmit data at a rate that is within 600 parts per million (ppm) of each other at all times. This is specified to allow bit rate clock sources with a ± 300 ppm tolerance.

17.4 Physical Layer Specifications

The following is a summary of the specifications for the physical layer of PCI Express on this device. For further details as well as the specifications of the transport and data link layer see *PCI Express Base Specification, Rev. 1.0a*.

17.4.1 Differential Transmitter (TX) Output

[Table 56](#) defines the specifications for the differential output at all transmitters (TXs). The parameters are specified at the component pins.

Table 57. Differential Receiver (RX) Input Specifications (continued)

Symbol	Parameter	Min	Nom	Max	Unit	Comments
$L_{TX-SKEW}$	Total Skew	—	—	20	ns	Skew across all lanes on a Link. This includes variation in the length of SKP ordered set (for example, COM and one to five symbols) at the RX as well as any delay differences arising from the interconnect itself.

Notes:

1. No test load is necessarily associated with this value.
2. Specified at the measurement point and measured over any 250 consecutive UIs. The test load in [Figure 50](#) must be used as the RX device when taking measurements (also see the receiver compliance eye diagram shown in [Figure 49](#)). If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as a reference for the eye diagram.
3. A $T_{RX-EYE} = 0.40$ UI provides for a total sum of 0.60 UI deterministic and random jitter budget for the transmitter and interconnect collected any 250 consecutive UIs. The $T_{RX-EYE-MEDIAN-to-MAX-JITTER}$ specification ensures a jitter distribution in which the median and the maximum deviation from the median is less than half of the total. UI jitter budget collected over any 250 consecutive TX UIs. Note that the median is not the same as the mean. The jitter median describes the point in time where the number of jitter points on either side is approximately equal as opposed to the averaged time value. If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as the reference for the eye diagram.
4. The receiver input impedance shall result in a differential return loss greater than or equal to 15 dB with the D+ line biased to 300 mV and the D– line biased to –300 mV and a common mode return loss greater than or equal to 6 dB (no bias required) over a frequency range of 50 MHz to 1.25 GHz. This input impedance requirement applies to all valid input levels. The reference impedance for return loss measurements for is 50 Ω to ground for both the D+ and D– line (that is, as measured by a vector network analyzer with 50- Ω probes—see [Figure 50](#)). Note: that the series capacitors CTX is optional for the return loss measurement.
5. Impedance during all LTSSM states. When transitioning from a fundamental reset to detect (the initial state of the LTSSM) there is a 5 ms transition time before receiver termination values must be met on all unconfigured lanes of a port.
6. The RX DC common mode Impedance that exists when no power is present or fundamental reset is asserted. This helps ensure that the receiver detect circuit does not falsely assume a receiver is powered on when it is not. This term must be measured at 300 mV above the RX ground.
7. It is recommended that the recovered TX UI is calculated using all edges in the 3500 consecutive UI interval with a fit algorithm using a minimization merit function. Least squares and median deviation fits have worked well with experimental and simulated data.

17.5 Receiver Compliance Eye Diagrams

The RX eye diagram in [Figure 49](#) is specified using the passive compliance/test measurement load (see [Figure 50](#)) in place of any real PCI Express RX component.

Note: In general, the minimum receiver eye diagram measured with the compliance/test measurement load (see [Figure 50](#)) is larger than the minimum receiver eye diagram measured over a range of systems at the input receiver of any real PCI Express component. The degraded eye diagram at the input receiver is due to traces internal to the package as well as silicon parasitic characteristics which cause the real PCI Express component to vary in impedance from the compliance/test measurement load. The input receiver eye diagram is implementation specific and is not specified. RX component designer must provide additional margin to adequately compensate for the degraded minimum receiver eye diagram (shown in [Figure 49](#)) expected at the input receiver based on some adequate combination of system simulations and the return loss measured looking into the RX package and silicon. The RX eye diagram must be aligned in time using the jitter median to locate the center of the eye diagram.

18.8 Receiver Eye Diagrams

For each baud rate at which an LP-serial receiver is specified to operate, the receiver shall meet the corresponding bit error rate specification (Table 66, Table 67, and Table 68) when the eye pattern of the receiver test signal (exclusive of sinusoidal jitter) falls entirely within the unshaded portion of the receiver input compliance mask shown in Figure 54 with the parameters specified in Table 69. The eye pattern of the receiver test signal is measured at the input pins of the receiving device with the device replaced with a $100\text{-}\Omega \pm 5\%$ differential resistive load.

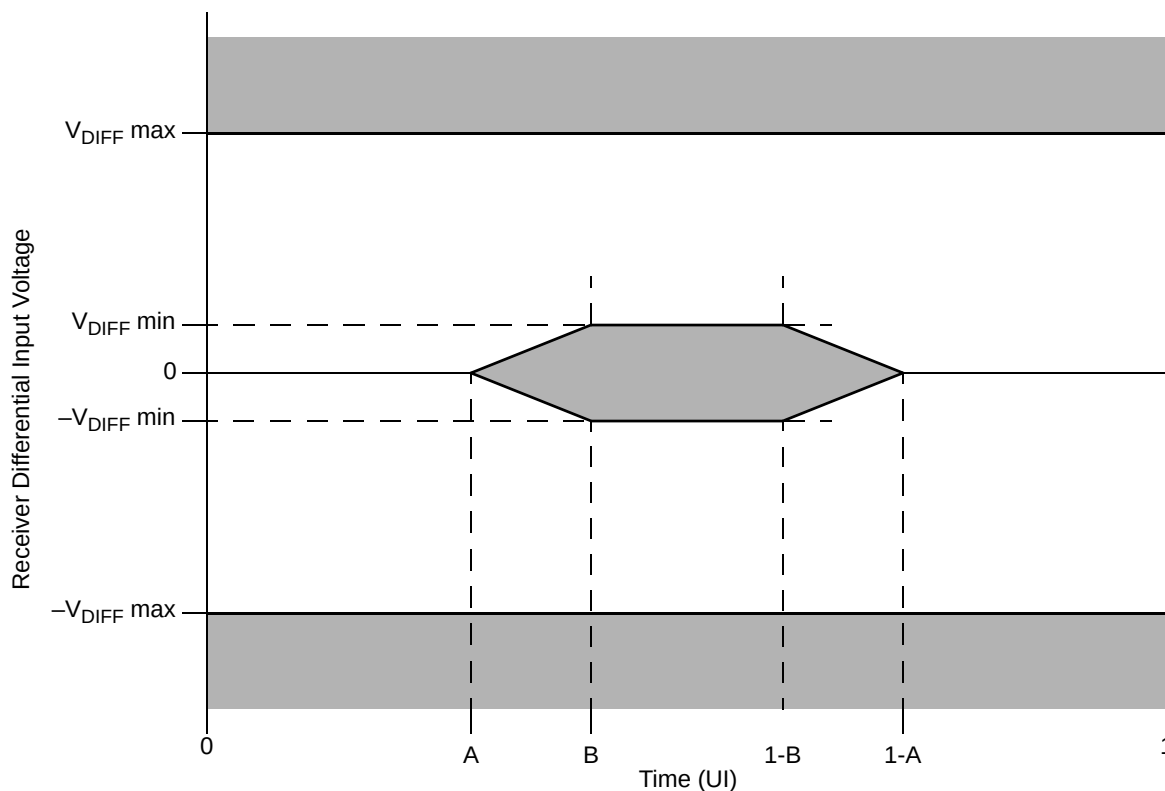


Figure 54. Receiver Input Compliance Mask

Table 69. Receiver Input Compliance Mask Parameters Exclusive of Sinusoidal Jitter

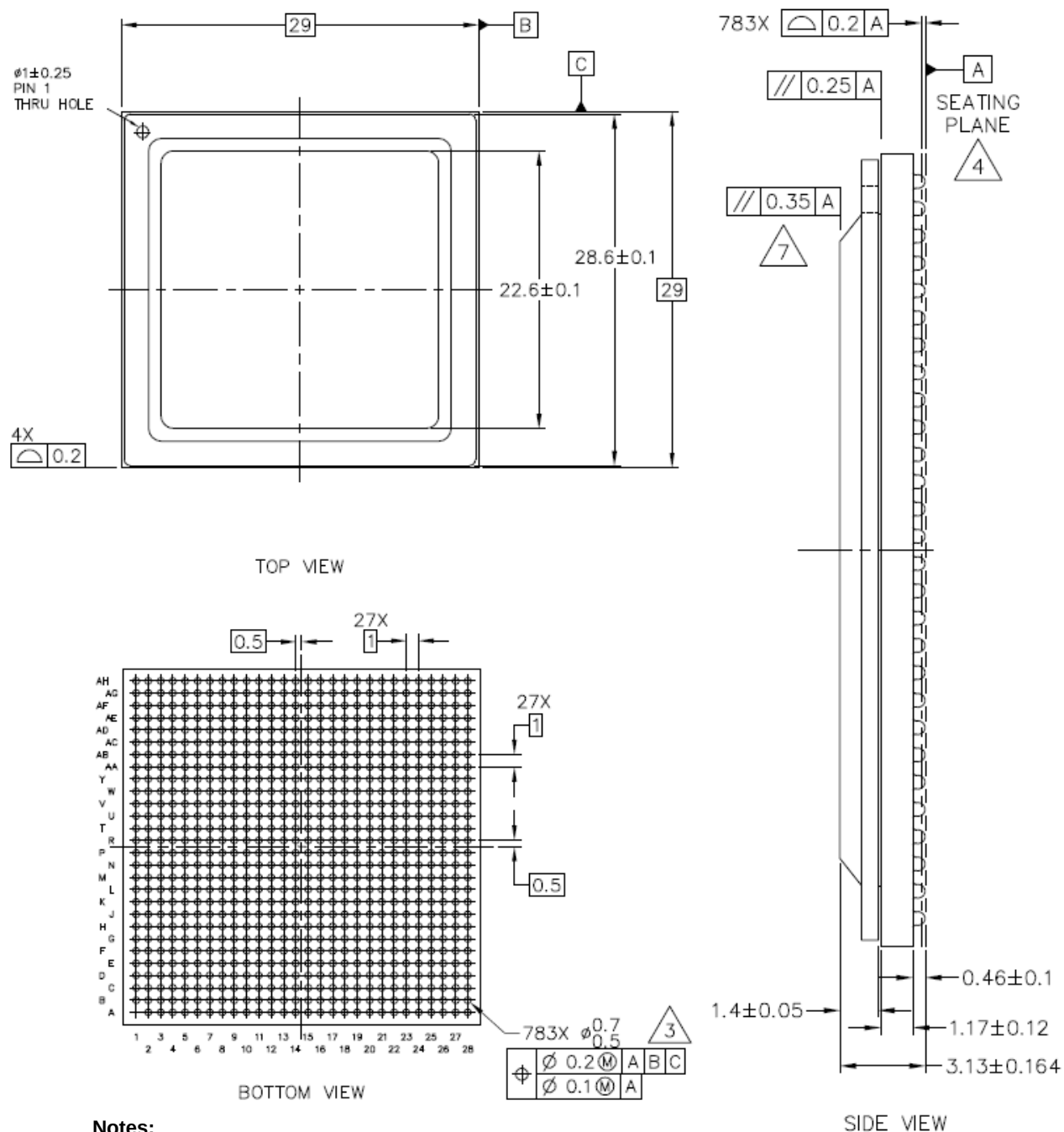
Receiver Type	$V_{DIFFmin}$ (mV)	$V_{DIFFmax}$ (mV)	A (UI)	B (UI)
1.25 GBaud	100	800	0.275	0.400
2.5 GBaud	100	800	0.275	0.400
3.125 GBaud	100	800	0.275	0.400

18.9 Measurement and Test Requirements

Since the LP-serial electrical specification are guided by the XAUI electrical interface specified in Clause 47 of IEEE Std. 802.3ae-2002, the measurement and test requirements defined here are similarly guided by Clause 47. Additionally, the CJPAT test pattern defined in Annex 48A of IEEE Std.

Notes:

1. All dimensions are in millimeters.
2. Dimensioning and tolerancing per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
5. Parallelism measurement shall exclude any effect of mark on top surface of package.
6. All dimensions are symmetric across the package center lines unless dimensioned otherwise.



Notes:

1. All dimensions are in millimeters.
2. Dimensioning and tolerancing per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
5. Capacitors may not be present on all devices.
6. Caution must be taken not to short capacitors or exposed metal capacitor pads on package top.
7. Parallelism measurement shall exclude any effect of mark on top surface of package.
8. All dimensions are symmetric across the package center lines unless dimensioned otherwise.

Figure 56. Mechanical Dimensions and Bottom Surface Nomenclature of the FC-PBGA with Stamped Lid

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{MWE}}$	E7	O	GV _{DD}	—
$\overline{\text{MCAS}}$	H7	O	GV _{DD}	—
$\overline{\text{MRAS}}$	L8	O	GV _{DD}	—
MCKE[0:3]	F10, C10, J11, H11	O	GV _{DD}	11
$\overline{\text{MCS}}[0:3]$	K8, J8, G8, F8	O	GV _{DD}	—
MCK[0:5]	H9, B15, G2, M9, A14, F1	O	GV _{DD}	—
$\overline{\text{MCK}}[0:5]$	J9, A15, G1, L9, B14, F2	O	GV _{DD}	—
MODT[0:3]	E6, K6, L7, M7	O	GV _{DD}	—
MDIC[0:1]	A19, B19	I/O	GV _{DD}	36
Local Bus Controller Interface				
LAD[0:31]	E27, B20, H19, F25, A20, C19, E28, J23, A25, K22, B28, D27, D19, J22, K20, D28, D25, B25, E22, F22, F21, C25, C22, B23, F20, A23, A22, E19, A21, D21, F19, B21	I/O	BV _{DD}	—
LDP[0:3]	K21, C28, B26, B22	I/O	BV _{DD}	—
LA[27]	H21	O	BV _{DD}	5, 9
LA[28:31]	H20, A27, D26, A28	O	BV _{DD}	5, 7, 9
$\overline{\text{LCS}}[0:4]$	J25, C20, J24, G26, A26	O	BV _{DD}	
$\overline{\text{LCS5/DMA_DREQ2}}$	D23	I/O	BV _{DD}	1
$\overline{\text{LCS6/DMA_DACK2}}$	G20	O	BV _{DD}	1
$\overline{\text{LCS7/DMA_DDONE2}}$	E21	O	BV _{DD}	1
$\overline{\text{LWE0/LBS0/LSDDQM}}[0]$	G25	O	BV _{DD}	5, 9
$\overline{\text{LWE1/LBS1/LSDDQM}}[1]$	C23	O	BV _{DD}	5, 9
$\overline{\text{LWE2/LBS2/LSDDQM}}[2]$	J21	O	BV _{DD}	5, 9
$\overline{\text{LWE3/LBS3/LSDDQM}}[3]$	A24	O	BV _{DD}	5, 9
LALE	H24	O	BV _{DD}	5, 8, 9
LBCTL	G27	O	BV _{DD}	5, 8, 9
LGPL0/LSDA10	F23	O	BV _{DD}	5, 9
LGPL1/LSDWE	G22	O	BV _{DD}	5, 9
LGPL2/ $\overline{\text{LOE/LSDRAS}}$	B27	O	BV _{DD}	5, 8, 9
LGPL3/ $\overline{\text{LSDCAS}}$	F24	O	BV _{DD}	5, 9
LGPL4/ $\overline{\text{LGTA/LUPWAIT/LPBSE}}$	H23	I/O	BV _{DD}	—
LGPL5	E26	O	BV _{DD}	5, 9
LCKE	E24	O	BV _{DD}	—
LCLK[0:2]	E23, D24, H22	O	BV _{DD}	—

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
SENSEVSS	M16	—	—	13
Analog Signals				
MVREF	A18	I Reference voltage signal for DDR	MVREF	—
SD_IMP_CAL_RX	L28	I	200Ω to GND	—
SD_IMP_CAL_TX	AB26	I	100Ω to GND	—
SD_PLL_TPA	U26	O	—	24

Notes:

1. All multiplexed signals are listed only once and do not re-occur. For example, $\overline{\text{LCS5/DMA_REQ2}}$ is listed only once in the local bus controller section, and is not mentioned in the DMA section even though the pin also functions as $\overline{\text{DMA_REQ2}}$.
2. Recommend a weak pull-up resistor (2–10 kΩ) be placed on this pin to OV_{DD} .
3. A valid clock must be provided at POR if $\text{TSEC4_TXD}[2]$ is set = 1.
4. This pin is an open drain signal.
5. This pin is a reset configuration pin. It has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7-kΩ pull-down resistor. However, if the signal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pull-up or active driver is needed.
6. Treat these pins as no connects (NC) unless using debug address functionality.
7. The value of $\text{LA}[28:31]$ during reset sets the CCB clock to SYSCLK PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See [Section 20.2, "CCB/SYSCLK PLL Ratio."](#)
8. The value of LALE , LGPL2 , and LBCTL at reset set the e500 core clock to CCB clock PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See the [Section 20.3, "e500 Core PLL Ratio."](#)
9. Functionally, this pin is an output, but structurally it is an I/O because it either samples configuration input during reset or because it has other manufacturing test functions. This pin therefore is described as an I/O for boundary scan.
10. This pin functionally requires a pull-up resistor, but during reset it is a configuration input that controls 32- vs. 64-bit PCI operation. Therefore, it must be actively driven low during reset by reset logic if the device is to be configured to be a 64-bit PCI device. See the *PCI Specification*.
11. This output is actively driven during reset rather than being three-stated during reset.
12. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
13. These pins are connected to the $\text{V}_{\text{DD}}/\text{GND}$ planes internally and may be used by the core power supply to improve tracking and regulation.
14. Internal thermally sensitive resistor.
15. No connections must be made to these pins if they are not used.
16. These pins are not connected for any use.
17. PCI specifications recommend that a weak pull-up resistor (2–10 kΩ) be placed on the higher order pins to OV_{DD} when using 64-bit buffer mode (pins $\text{PCI_AD}[63:32]$ and $\text{PCI1_C_BE}[7:4]$).
19. If this pin is connected to a device that pulls down during reset, an external pull-up is required to drive this pin to a safe state during reset.
20. This pin is only an output in FIFO mode when used as Rx flow control.
24. Do not connect.

Table 72. MPC8547E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
DFT				
L1_TSTCLK	AC25	I	OV _{DD}	25
L2_TSTCLK	AE22	I	OV _{DD}	25
$\overline{\text{LSSD_MODE}}$	AH20	I	OV _{DD}	25
$\overline{\text{TEST_SEL}}$	AH14	I	OV _{DD}	25
Thermal Management				
THERM0	AG1	—	—	14
THERM1	AH1	—	—	14
Power Management				
ASLEEP	AH18	O	OV _{DD}	9, 19, 29
Power and Ground Signals				
GND	A11, B7, B24, C1, C3, C5, C12, C15, C26, D8, D11, D16, D20, D22, E1, E5, E9, E12, E15, E17, F4, F26, G12, G15, G18, G21, G24, H2, H6, H8, H28, J4, J12, J15, J17, J27, K7, K9, K11, K27, L3, L5, L12, L16, N11, N13, N15, N17, N19, P4, P9, P12, P14, P16, P18, R11, R13, R15, R17, R19, T4, T12, T14, T16, T18, U8, U11, U13, U15, U17, U19, V4, V12, V18, W6, W19, Y4, Y9, Y11, Y19, AA6, AA14, AA17, AA22, AA23, AB4, AC2, AC11, AC19, AC26, AD5, AD9, AD22, AE3, AE14, AF6, AF10, AF13, AG8, AG27, K28, L24, L26, N24, N27, P25, R28, T24, T26, U24, V25, W28, Y24, Y26, AA24, AA27, AB25, AC28, L21, L23, N22, P20, R23, T21, U22, V20, W23, Y21, U27	—	—	—
OV _{DD}	V16, W11, W14, Y18, AA13, AA21, AB11, AB17, AB24, AC4, AC9, AC21, AD6, AD13, AD17, AD19, AE10, AE8, AE24, AF4, AF12, AF22, AF27, AG26	Power for PCI and other standards (3.3 V)	OV _{DD}	—
LV _{DD}	N8, R7, T9, U6	Power for TSEC1 and TSEC2 (2.5 V, 3.3 V)	LV _{DD}	—
TV _{DD}	W9, Y6	Power for TSEC3 and TSEC4 (2.5 V, 3.3 V)	TV _{DD}	—
GV _{DD}	B3, B11, C7, C9, C14, C17, D4, D6, D10, D15, E2, E8, E11, E18, F5, F12, F16, G3, G7, G9, G11, H5, H12, H15, H17, J10, K3, K12, K16, K18, L6, M4, M8, M13	Power for DDR1 and DDR2 DRAM I/O voltage (1.8 V, 2.5 V)	GV _{DD}	—

Table 73. MPC8545E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
FIFO1_RXC2	P5	I	LV _{DD}	104
Reserved	R1	—	—	104
Reserved	P10	—	—	105
FIFO1_TXC2	P7	O	LV _{DD}	15
cfg_dram_type1	R10	I	LV _{DD}	5
Three-Speed Ethernet Controller (Gigabit Ethernet 3)				
TSEC3_TXD[3:0]	V8, W10, Y10, W7	O	TV _{DD}	5, 9, 29
TSEC3_RXD[3:0]	Y1, W3, W5, W4	I	TV _{DD}	—
TSEC3_GTX_CLK	W8	O	TV _{DD}	—
TSEC3_RX_CLK	W2	I	TV _{DD}	—
TSEC3_RX_DV	W1	I	TV _{DD}	—
TSEC3_RX_ER	Y2	I	TV _{DD}	—
TSEC3_TX_CLK	V10	I	TV _{DD}	—
TSEC3_TX_EN	V9	O	TV _{DD}	30
TSEC3_TXD[7:4]	AB8, Y7, AA7, Y8	O	TV _{DD}	5, 9, 29
TSEC3_RXD[7:4]	AA1, Y3, AA2, AA4	I	TV _{DD}	—
Reserved	AA5	—	—	15
TSEC3_COL	Y5	I	TV _{DD}	—
TSEC3_CRS	AA3	I/O	TV _{DD}	31
TSEC3_TX_ER	AB6	O	TV _{DD}	—
DUART				
UART_CTS[0:1]	AB3, AC5	I	OV _{DD}	—
UART_RTS[0:1]	AC6, AD7	O	OV _{DD}	—
UART_SIN[0:1]	AB5, AC7	I	OV _{DD}	—
UART_SOUT[0:1]	AB7, AD8	O	OV _{DD}	—
I²C interface				
IIC1_SCL	AG22	I/O	OV _{DD}	4, 27
IIC1_SDA	AG21	I/O	OV _{DD}	4, 27
IIC2_SCL	AG15	I/O	OV _{DD}	4, 27
IIC2_SDA	AG14	I/O	OV _{DD}	4, 27
SerDes				
SD_RX[0:3]	M28, N26, P28, R26	I	XV _{DD}	—
SD_RX[0:3]	M27, N25, P27, R25	I	XV _{DD}	—
SD_TX[0:3]	M22, N20, P22, R20	O	XV _{DD}	—

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{MWE}}$	E7	O	GV _{DD}	—
$\overline{\text{MCAS}}$	H7	O	GV _{DD}	—
$\overline{\text{MRAS}}$	L8	O	GV _{DD}	—
MCKE[0:3]	F10, C10, J11, H11	O	GV _{DD}	11
$\overline{\text{MCS}}[0:3]$	K8, J8, G8, F8	O	GV _{DD}	—
MCK[0:5]	H9, B15, G2, M9, A14, F1	O	GV _{DD}	—
$\overline{\text{MCK}}[0:5]$	J9, A15, G1, L9, B14, F2	O	GV _{DD}	—
MODT[0:3]	E6, K6, L7, M7	O	GV _{DD}	—
MDIC[0:1]	A19, B19	I/O	GV _{DD}	36
Local Bus Controller Interface				
LAD[0:31]	E27, B20, H19, F25, A20, C19, E28, J23, A25, K22, B28, D27, D19, J22, K20, D28, D25, B25, E22, F22, F21, C25, C22, B23, F20, A23, A22, E19, A21, D21, F19, B21	I/O	BV _{DD}	—
LDP[0:3]	K21, C28, B26, B22	I/O	BV _{DD}	—
LA[27]	H21	O	BV _{DD}	5, 9
LA[28:31]	H20, A27, D26, A28	O	BV _{DD}	5, 7, 9
$\overline{\text{LCS}}[0:4]$	J25, C20, J24, G26, A26	O	BV _{DD}	—
$\overline{\text{LCS5/DMA_DREQ2}}$	D23	I/O	BV _{DD}	1
$\overline{\text{LCS6/DMA_DACK2}}$	G20	O	BV _{DD}	1
$\overline{\text{LCS7/DMA_DDONE2}}$	E21	O	BV _{DD}	1
$\overline{\text{LWE0/LBS0/LSDDQM}}[0]$	G25	O	BV _{DD}	5, 9
$\overline{\text{LWE1/LBS1/LSDDQM}}[1]$	C23	O	BV _{DD}	5, 9
$\overline{\text{LWE2/LBS2/LSDDQM}}[2]$	J21	O	BV _{DD}	5, 9
$\overline{\text{LWE3/LBS3/LSDDQM}}[3]$	A24	O	BV _{DD}	5, 9
LALE	H24	O	BV _{DD}	5, 8, 9
LBCTL	G27	O	BV _{DD}	5, 8, 9
LGPL0/LSDA10	F23	O	BV _{DD}	5, 9
LGPL1/LSDWE	G22	O	BV _{DD}	5, 9
LGPL2/LOE/LSDRAS	B27	O	BV _{DD}	5, 8, 9
LGPL3/LSDCAS	F24	O	BV _{DD}	5, 9
LGPL4/LGTA/LUPWAIT/LPBSE	H23	I/O	BV _{DD}	—
LGPL5	E26	O	BV _{DD}	5, 9
LCKE	E24	O	BV _{DD}	—
LCLK[0:2]	E23, D24, H22	O	BV _{DD}	—

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
JTAG				
TCK	AG28	I	OV _{DD}	—
TDI	AH28	I	OV _{DD}	12
TDO	AF28	O	OV _{DD}	—
TMS	AH27	I	OV _{DD}	12
$\overline{\text{TRST}}$	AH23	I	OV _{DD}	12
DFT				
L1_TSTCLK	AC25	I	OV _{DD}	25
L2_TSTCLK	AE22	I	OV _{DD}	25
$\overline{\text{LSSD_MODE}}$	AH20	I	OV _{DD}	25
TEST_SEL	AH14	I	OV _{DD}	109
Thermal Management				
THERM0	AG1	—	—	14
THERM1	AH1	—	—	14
Power Management				
ASLEEP	AH18	O	OV _{DD}	9, 19, 29
Power and Ground Signals				
GND	A11, B7, B24, C1, C3, C5, C12, C15, C26, D8, D11, D16, D20, D22, E1, E5, E9, E12, E15, E17, F4, F26, G12, G15, G18, G21, G24, H2, H6, H8, H28, J4, J12, J15, J17, J27, K7, K9, K11, K27, L3, L5, L12, L16, N11, N13, N15, N17, N19, P4, P9, P12, P14, P16, P18, R11, R13, R15, R17, R19, T4, T12, T14, T16, T18, U8, U11, U13, U15, U17, U19, V4, V12, V18, W6, W19, Y4, Y9, Y11, Y19, AA6, AA14, AA17, AA22, AA23, AB4, AC2, AC11, AC19, AC26, AD5, AD9, AD22, AE3, AE14, AF6, AF10, AF13, AG8, AG27, K28, L24, L26, N24, N27, P25, R28, T24, T26, U24, V25, W28, Y24, Y26, AA24, AA27, AB25, AC28, L21, L23, N22, P20, R23, T21, U22, V20, W23, Y21, U27	—	—	—
OV _{DD}	V16, W11, W14, Y18, AA13, AA21, AB11, AB17, AB24, AC4, AC9, AC21, AD6, AD13, AD17, AD19, AE10, AE8, AE24, AF4, AF12, AF22, AF27, AG26	Power for PCI and other standards (3.3 V)	OV _{DD}	—
LV _{DD}	N8, R7, T9, U6	Power for TSEC1 and TSEC2 (2.5 V, 3.3 V)	LV _{DD}	—

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
SENSEVSS	M16	—	—	13
Analog Signals				
MVREF	A18	I Reference voltage signal for DDR	MVREF	—
SD_IMP_CAL_RX	L28	I	200 Ω ($\pm 1\%$) to GND	—
SD_IMP_CAL_TX	AB26	I	100 Ω ($\pm 1\%$) to GND	—
SD_PLL_TPA	U26	O	AVDD_SRDS	24

Note: All note references in this table use the same numbers as those for [Table 71](#). See [Table 71](#) for the meanings of these notes.

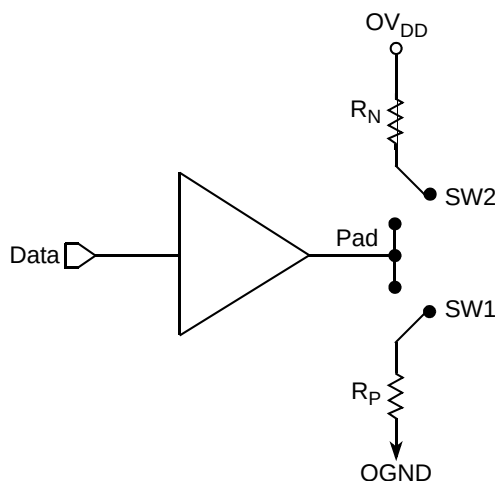


Figure 61. Driver Impedance Measurement

This table summarizes the signal impedance targets. The driver impedances are targeted at minimum V_{DD} , nominal OV_{DD} , 105°C.

Table 86. Impedance Characteristics

Impedance	Local Bus, Ethernet, DUART, Control, Configuration, Power Management	PCI	DDR DRAM	Symbol	Unit
R_N	43 Target	25 Target	20 Target	Z_0	W
R_P	43 Target	25 Target	20 Target	Z_0	W

Note: Nominal supply voltages. See Table 1, $T_j = 105^\circ\text{C}$.

22.8 Configuration Pin Muxing

The device provides the user with power-on configuration options which can be set through the use of external pull-up or pull-down resistors of 4.7 k Ω on certain output pins (see customer visible configuration pins). These pins are generally used as output only pins in normal operation.

While $\overline{\text{HRESET}}$ is asserted however, these pins are treated as inputs. The value presented on these pins while $\overline{\text{HRESET}}$ is asserted, is latched when $\overline{\text{HRESET}}$ deasserts, at which time the input receiver is disabled and the I/O circuit takes on its normal function. Most of these sampled configuration pins are equipped with an on-chip gated resistor of approximately 20 k Ω . This value must permit the 4.7-k Ω resistor to pull the configuration pin to a valid logic low level. The pull-up resistor is enabled only during $\overline{\text{HRESET}}$ (and for platform/system clocks after $\overline{\text{HRESET}}$ deassertion to ensure capture of the reset value). When the input receiver is disabled the pull-up is also, thus allowing functional operation of the pin as an output with minimal signal quality or delay disruption. The default value for all configuration bits treated this way has been encoded such that a high voltage level puts the device into the default state and external resistors are needed only when non-default settings are required by the user.

Careful board layout with stubless connections to these pull-down resistors coupled with the large value of the pull-down resistor minimizes the disruption of signal quality or speed for output pins thus configured.